Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/604,123	KUMPON ET AL.
Examiner	Art Unit
Tianiie Chen	2652

	SEAR	CHED	
	027.11		1
Class	Subclass	Date	Examiner
Updated		8/15/2005	TJ
	<u> </u>		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH N (INCLUDING SEARC	OTES H STRATEGY	<b>(</b> )
	DATE	EXMR
		<del> </del>
•		
		<u> </u>
		ļ
·		
	İ	